

Amendments to the Specification

Please delete the paragraph at Page 7, lines 14-18 as follows:

~~A test method of a semiconductor memory device comprises steps of; latching data at a page latch via a data bus on which the data are transferred, transferring the data latched in the page latch to a cell matrix for stored the data at a first mode and to a read out circuit at a second mode for testing whether or not an error occurs at a data transfer circuit group including the data bus, the page latch and read out circuit”.~~